SN54LV08 ... J OR W PACKAGE

SCLS186C - FEBRUARY 1993 - REVISED APRIL 1996

- **EPIC**[™] (Enhanced-Performance Implanted CMOS) 2-µ Process
- Typical V_{OLP} (Output Ground Bounce) < 0.8 V at V_{CC} , $T_A = 25^{\circ}C$
- Typical V_{OHV} (Output V_{OH} Undershoot) > 2 V at V_{CC}, $T_A = 25^{\circ}C$
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JEDEC Standard JESD-17
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Ceramic (J) 300-mil DIPs

description

These quadruple 2-input positive-AND gates are designed for 2.7-V to 5.5-V V_{CC} operation.

The 'LV08 perform Boolean function $Y = A \cdot B$ or

 $Y = \overline{\overline{A} + \overline{B}}$ in positive logic.

The SN74LV08 is available in TI's shrink small-outline package (DB), which provides the same I/O pin count and functionality of standard small-outline packages in less than half the printed-circuit-board area.

The SN54LV08 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74LV08 is characterized for operation from -40°C to 85°C.

FU	NCTION (each g							
INPUTS OUTPUT								
Α	B Y							
н	Н	Н						
L	Х	L						

L

Х



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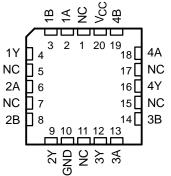
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SN74LV08	D, DB, (TOP V		W PACKAGE
1A [14	Vcc
1B [2	13	4B
1Y [3	12	4A
2A [4	11	4Y
2B [5	10	3B
2Y [6	9	ЗA
GND [7	8	3Y

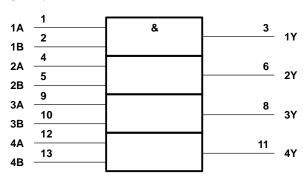
SN54LV08 ... FK PACKAGE (TOP VIEW)



NC - No internal connection

SCLS186C - FEBRUARY 1993 - REVISED APRIL 1996

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, DB, J, PW, and W packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

logic diagram, each gate (positive logic)

Y

Α

R

Supply voltage range, V _{CC}	\ldots -0.5 V to 7 V
Input voltage range, V _I (see Note 1)	-0.5 V to V _{CC} + 0.5 V
Output voltage range, V _O (see Notes 1 and 2)	-0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0 or V _I > V _{CC})	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±25 mA
Continuous current through V _{CC} or GND	±50 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 3): D package	1.25 W
DB or DW package	e 0.5 W
Storage temperature range, T _{stg}	

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. This value is limited to 7 V maximum.

3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.



SCLS186C - FEBRUARY 1993 - REVISED APRIL 1996

recommended operating conditions (see Note 4)

			SN54	SN54LV08		54LV08 SN74LV08			LINUT
			MIN MAX		MIN MAX		UNIT		
VCC	Supply voltage		2.7	5.5	2.7	5.5	V		
	High-level input voltage	V_{CC} = 2.7 V to 3.6 V	2		2		v		
VIH	High-level liput voltage	V_{CC} = 4.5 V to 5.5 V	3.15		3.15		v		
V	Low level input voltage	$V_{CC} = 2.7 V \text{ to } 3.6 V$		0.8		0.8	V		
VIL	Low-level input voltage	$V_{CC} = 4.5 V \text{ to } 5.5 V$		1.65		1.65	v		
VI	Input voltage		0	Vcc	0	VCC	V		
VO	Output voltage		0	VCC	0	VCC	V		
lau	High lovel output ourrest	$V_{CC} = 2.7 V \text{ to } 3.6 V$	na	-6		-6	mA		
ЮН	High-level output current	V_{CC} = 4.5 V to 5.5 V	Po	-12		-12	mA		
le.		V _{CC} = 2.7 V to 3.6 V	Y	6		6	mA		
IOL	Low-level output current	V_{CC} = 4.5 V to 5.5 V		12		12	mA		
$\Delta t / \Delta v$	Input transition rise or fall rate		0	100	0	100	ns/V		
TA	Operating free-air temperature		-55	125	-40	85	°C		

NOTE 4: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS		y +	SI	SN54LV08			SN74LV08			
PARAMETER			Vcc [†]	MIN	TYP	MAX	MIN	TYP	MAX	UNIT	
	I _{OH} = −100 μA		MIN to MAX	V _{CC} –0.	2		V _{CC} -0.	2			
VOH	I _{OH} = -6 mA		3 V	2.4			2.4			V	
	I _{OH} = -12 mA		4.5 V	3.6			3.6				
	I _{OL} = 100 μA		MIN to MAX			0.2			0.2		
VOL	IOL = 6 mA		3 V		1	0.4			0.4	V	
	I _{OL} = 12 mA		4.5 V		RE	0.55			0.55		
1.			3.6 V		7	±1			±1	A	
tι	$V_{I} = V_{CC} \text{ or } GND$	5.5 V		S	±1			±1	μA		
1			3.6 V	0	7	20			20	A	
lcc	$V_{I} = V_{CC}$ or GND	I ^O = 0	5.5 V	2		20			20	μA	
∆ICC	One input at V _{CC} – 0.6 V	Other inputs at V _{CC} or GND	3 V to 3.6 V			500			500	μΑ	
<u> </u>			3.3 V		2.5			2.5		~	
Ci	$V_I = V_{CC}$ or GND		5 V		2.6			2.6		pF	

[†] For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.

switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

57.011 70			SN54LV08									
PARAMETER	FROM (INPUT)	TO (OUTPUT)	Vcc	= 5 V ± 0).5 V 💦	Vcc =	= 3.3 V ±	0.3 V	Vcc =	= 2.7 V	UNIT	
	(MIN	TYP	MAX	MIN	TYP	MAX	MIN	MAX		
^t pd	A	Y		7	110	~	10	15		17	ns	

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SCLS186C - FEBRUARY 1993 - REVISED APRIL 1996

switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

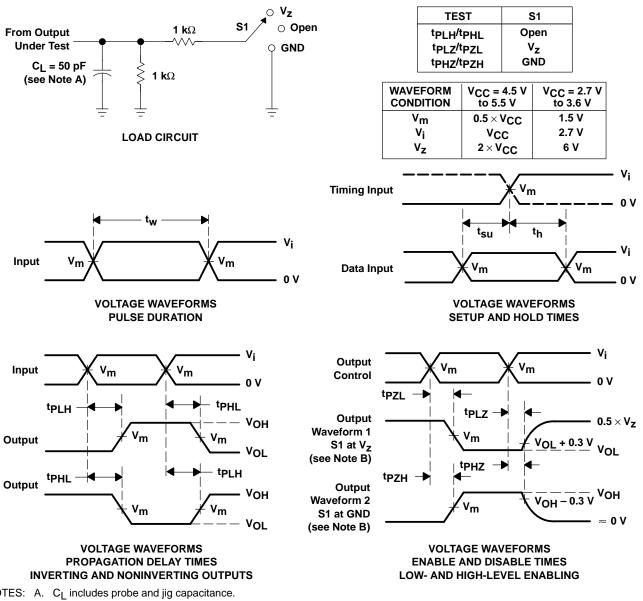
		=-				SN74	LV08				
PARAMETER	FROM (INPUT)	TO (OUTPUT)	VCC	= 5 V ± 0).5 V	V _{CC} =	= 3.3 V \pm	0.3 V	V _{CC} =	= 2.7 V	UNIT
	((0011 01)	MIN	TYP	MAX	MIN	TYP	MAX	MIN	MAX	
^t pd	A	Y		7	11		10	15		17	ns

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	Vcc	TYP	UNIT
C	$C_{1} = 50 \text{ pc}$ $f = 10 \text{ MHz}$	3.3 V	24	~	
Cpd	Power dissipation capacitance per gate	$C_{L} = 50 \text{ pF}, f = 10 \text{ MHz}$	5 V	29	pF



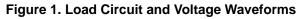
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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. tpLH and tpHL are the same as tpd.





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